

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	98	@ad<="20020930" and (257/48). ccls. and 'DRAM'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 08:51
L2	736	@ad<="20020930" and (257/48). ccls. and 'test'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 08:50
L3	126	@ad<="20020930" and (257/48). ccls. and 'test structure'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 08:50
L4	314	@ad<="20020930" and 'DRAM' and 'test structure'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 08:52
L5	37	@ad<="20020930" and 'trench capacitor' and 'test structure'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 08:52
L6	1	"6140199".PN.	USPAT; USOCR	OR	ON	2004/11/22 08:53
L7	1	"5945704".PN.	USPAT; USOCR	OR	ON	2004/11/22 08:54
L8	1	"5914512".PN.	USPAT; USOCR	OR	ON	2004/11/22 08:55
L9	3590	@ad<="20020930" and (324/765). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:14
L10	366	@ad<="20020930" and (324/769). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:05
L11	3425	@ad<="20020930" and (324/754). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:06
L14	3589	@ad<="20020930" and (438/17). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:50

L16	2	("6624031").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/22 09:10
L18	187	@ad<="20020930" and (324/548). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:16
L20	109	@ad<="20020930" and 'capacitor' same 'diffusion' same 'test'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:17
L21	118	@ad<="20020930" and 'capacitor' same 'diffusion' same 'measurement'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:28
L22	43	@ad<="20020930" and 'memory' and 'out diffusion' and 'trench' and 'test'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:29
L24	536	@ad<="20020930" and (438/243). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:56
L25	479	@ad<="20020930" and (438/386). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:51
L26	198	@ad<="20020930" and (438/388-391).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:51
L27	78	@ad<="20020930" and (438/392). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:51
L29	988	@ad<="20020930" and (257/301). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:57
L30	1584	@ad<="20020930" and (257/302-305).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:54

L31	312	@ad<="20020930" and (438/244). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:56
L32	204	@ad<="20020930" and (257/e29. 346).ccls	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:57
L33	292	@ad<="20020930" and (257/e21. 396).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:57
S5	2	"20040061111"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 14:22
S7	988	@ad<="20020930" and (257/301). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 14:25
S8	1065	@ad<="20020930" and (257/48). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:04
S9	642	@ad<="20020930" and (438/15). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/22 09:07
S10	72	'test structure' and 'memory cell' and 'trench'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 14:44
S11	4	'test structure' same 'doping region' and 'trench capacitor'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 14:47
S12	4	'test structure' and 'trench capacitor' and 'buried plate' and 'buried strap'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 14:49
S13	15099	((204/192.11) or (204/192.13) or (204/192.15) or (324/754) or (257/750) or (257/758) or (438/396) or (438/256)).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/19 14:56

S14	287	S13 and @ad<="20020930" and 'trench capacitor'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 15:01
S15	1	"5969380".PN	USPAT; USOCR	OR	ON	2004/11/19 14:59
S16	1944	@ad<="20020930" and (257/306-308).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 15:03
S17	7	@ad<="20020930" and (257/306-308).ccls. and 'test structure'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 15:05
S18	37	@ad<="20020930" and 'trench capacitor' and 'test structure'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 15:19
S19	1	"6087189".PN	USPAT; USOCR	OR	ON	2004/11/19 15:11
S20	199	@ad<="20020930" and 'trench capacitor' and 'out diffusion'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 15:17
S21	284	@ad<="20020930" and 'trench capacitor' same 'buried plate'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 15:42
S22	52	@ad<="20020930" and 'trench capacitor' same 'buried plate' and 'out diffusion'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 15:22
S23	5	@ad<="20020930" and 'trench capacitor' and 'buried plate' with 'test'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 15:42
S24	6	@ad<="20020930" and 'trench capacitor' and 'buried plate' with 'measure'	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/19 15:42